1.5/45 Mb/s (DS1/DS3) Line Interface

Agilent Technologies Broadband Series Test System

E1616A

A line interface for the modular Broadband Series Test System, the E1616A generates and analyzes ATM cell streams contained within DS1 or DS3 framing formats.

Product Features

- Cell based implementation
- Selectable mode as DS1 or DS3
- Selectable mapping: direct or PLCP
- Provides physical layer measurements, as well as error and alarm generation
- Operates in Terminal, Repeater and Local Loopback modes
- Internal traffic generator has 1 foreground channel and up to 100 background channels
- Works with Cell Protocol Processor

The Agilent Technologies E1616A 1.5/45 Mb/s (DS1/DS3) Line Interface generates and analyses ATM cell streams contained within a DS1 or DS3 framing format. It is a single-slot module that provides test capability at the physical and ATM cell layers for the Agilent E4200/E4210 Broadband Series Test System.

The E1616A is capable of the following mappings:

- DS3 direct mapping as per ANSI draft T1S1/94-243
- DS3 PLCP mapping as per UNI Version 3.0
- DS1 direct mapping as per ITU recommendation G.804
- TDS1 PLCP mapping as per Bellcore TR-TSV-000773 Issue 1, June 1991

Line interface modules not only connect the device or system under test to your Broadband Series Test System, but also provide physical, convergence, and ATM cell testing capabilities.

Transmission test functionality includes:

- Traffic generation
- Cell error, loss & delay measurements
- Traffic capture & playback

Typical Applications

The Broadband Series Test System (BSTS) is a modular test platform for high-speed ATM transmission and protocol testing. The BSTS can perform comprehensive testing of all layers, from physical through higher services. Due to its modular nature, you can create a customized configuration that suits your specific test needs. The fully-programmable BSTS is ideal for R&D engineering, product development, quality assurance, performance, type approval, and conformance testing.

The E1616A 1.5/45 Mb/s (DS1/DS3) Line Interface can be used in conjunction with other BSTS line interfaces, dedicated test modules, and test software to perform these tests.

Key Features

Generate Normal or Abnormal Test Traffic

Create and detect erroneous test traffic on demand to test the robustness of a protocol implementation. Sophisticated protocol data unit builder, sequencing, and library functions let you easily create complex and realistic traffic. You can generate test traffic in the foreground channel, and use up to 100 background channels to simulate loading effects.

Cell Error, Loss & Delay Measurements

Bit error rate testing is done by placing PRBS patterns in cells, and looping these cells back through a system under test. The received cells are analyzed to detect PRBS errors. These errors can then be used as a trigger to capture data.

Cell delay, interarrival time, and loss measurements are easily accomplished with the BSTS. Timestamps are inserted in cells transmitted by the line interface. These cells can then be captured, and graphs for both cell delay and cell interarrival time displayed.

Sequence numbers are transmitted in AAL-1 PDUs and looped back through a system under test. The lost cells can then be detected and counted with statistics or used as a trigger to capture data.

You can generate physical and convergence layer errors and alarms. You can also capture and playback convergence layer frames.

Real-time statistics can be gathered for the physical, convergence and cell layers. Statistics can be reported as errored seconds, event counts,or as error ratios.

Traffic Capture & Playback

Traffic can be captured with a large capture memory. Complete control is available -- continuously capture with memory buffer overlapping, or trigger on user-defined events. Captured traffic can be played back with automatic decoding into an English-language display. Terminology from standards documents is used wherever possible.

Since high-speed networks carry considerable volumes of traffic, you can increase your test productivity by using filters and triggers to display or capture only traffic of interest. Filters let you select virtual channels or paths of interest.

Triggers can be used to capture data matching a specific pattern. For example, triggers can be used to capture cells with header errors or sequence number errors, or upon changes in convergence layer frame bytes.

Configuration

Line interface modules can perform physical layer testing with a minimal BSTS configuration consisting of a line interface module and chassis. A complete range of test software applications and dedicated test modules is available to perform upper layer testing.

The E4209 Cell Protocol Processor provides monitoring and simulation test functions at the ATM and adaptation layers by executing optional protocol testing software applications. The CPP performs many functions in hardware that are usually done in software -- such as an automatic segmentation and reassembly engine for sophisticated real-time ATM, AAL and other higher layer protocol testing.

The E4219 ATM Network Impairment Emulator module lets you find the limits of performance by inserting impairments into an ATM cell stream. Route in your test cells, set cell delay and loss values to emulate a real-world network, connect the impaired cell stream output to your system under test, and see what happens.

Your local Agilent Technologies field engineer will help you select the best test system configuration to meet your needs.
Since the Broadband Series Test System is a flexible and modular ATM/B-ISDN test platform, you can maximize the return on your test equipment investment by selecting a chassis, line interfaces, dedicated hardware modules, and test software that suits your specific needs. Remember that you can always add extra software or modules at any time.

Warranty & Support Options

All BSTS hardware components are warranted for a period of 3 years. Products must be returned to an authorized Agilent service center for service. At the time of purchase you may select warranty option W01, a no-charge option which converts the standard 3-year return to Agilent warranty to a 1-year on-site warranty.

Support option UK6, available at time of purchase, is a standards-compliant calibration which ensures that your BSTS test system operates within specified tolerances. A certificate of calibration is issued for compliance with ISO 9000 standards which require that records documenting the calibration of measuring and test equipment are maintained. Certificates of calibration are not available for products which do not contain components requiring calibration (such as software).

Two other types of calibration, commercial and standards-complaint, are available at any time from your local Agilent service center. Both provide test data and a certificate for your records. With a commercial calibration, any problems are resolved as they are detected, and test data reflecting performance of your calibrated test system is provided. The standards-compliant calibration provides comprehensive before and after test data to document problem resolution.

If you should have an out-of-warranty test system, you can arrange for service simply by contacting your local Agilent sales office.

Product Numbers

- **E1616A** 1.5/45 Mb/s (DS1/DS3) Line Interface
- **E4200A/B** BSTS Form-7 Transportable Chassis
- **E4210A/B** BSTS Form-13 Mainframe Chassis
- **E4209A/B** Cell Protocol Processor
- **E4219A** ATM Network Impairment Emulator

Traffic Generation

Modes

Three Tx/Rx modes are available. In Terminal mode, full signal generation and analysis functions are available. In Repeater mode, the received signal is re-transmitted (physical layer loopback). In Local Loopback mode, the transmit signal is electrically looped to the receiver.

ATM Cell Generation

The transmitted cell stream can contain ATM cells generated internally by the E1616A, and ATM cells generated by an optional E4209 Cell Protocol Processor module. ATM cells generated on-board can consist of one foreground channel to stimulate the channel under test, and up to one hundred background channels for loading purposes. Fill cells are used to occupy unused bandwidth.

Total Bandwidth	• DS1: 1.413 Mb/s • DS3: 40.704 Mb/s
Modes	• User-Network Interface (UNI) or Network-Node Interface (NNI)
HEC	• Automatic generation
Fill Cells	• Idle or unassigned
Channel Priority Order	• Foreground, background, CPP (highest to lowest priority)
Channel Control	• VCI • VPI • GFC • Payload Type • Cell Loss Priority
SAR-PDU Support	• AAL-0 • AAL-1

Foreground Channel

Bandwidth	• DS1: 100 b/s to 1.413 Mb/s • DS3: 100 b/s to 40.704 Mb/s
Accuracy	• +/- 0.02 ppm
Distribution	• Off • Single burst • Periodic (according to the specified bandwidth)
Channel Depth	• 1500 cells (variable)
Cell Payload	• Timestamp • Single cell PRBS • Cross cell PRBS • Data pattern • Byte access

Background Channels

Number of Channels	• Up to 100
Bandwidth	• DS1: 3 kb/s to 1.413 Mb/s • DS3: 3 kb/s to 40.704 Mb/s
Accuracy	• +/- 10 ppm
Distribution	• Off • Periodic
Channel Density	• Bandwidth and cell distribution for each background channel is individually assignable up to maximum bandwidth
Channel Depth	• 16 cells
Cell Payload	• Single cell PRBS • Data pattern • Byte access

Cell Payloads

Payloads	• Timestamp (32-bit departure timestamp value with 100 nanosecond resolution) • Cross cell PRBS-9 • PRBS-15 (inverted and not inverted) • PRBS-23 • Single cell PRBS-9 • Data pattern or byte access
Data Patterns	• User edit • AA55h or FF00 • Incrementing (value of each successive byte is incremented by 1)
Byte Access	• Payload of all cells in the selected channel can be edited by the user in an active channel environment, or off-line as a sequence of PDUs • AAL-1 automatically inserts first payload byte containing SN/SNP values and CSI bit

Erroring Control

Error conditions can be introduced to simulate alarm signals and signal stressing. Error stressing is used to generate incorrect bytes in a test signal.

Error Stressing Control	• Off • On • Pulse On (error condition is normally off; pulses on) • Pulse off (normally on; pulses off) • Sequence On (normally off; alternates on/off/on) • Sequence Off (normally on; alternates off/on/off)
ATM Error Injection	• Cell header or payload bytes with bit error masking
Cell Loss	• Sequence Number in the SAR-PDU is skipped and a fill cell is inserted
PRBS Error Add	• Single bit error add to the PRBS pattern in the cell payload

DS1, DS3 & PLCP Stressing

DS1/PLCP Alarm Generation	• AIS • Yellow
DS3/PLCP Alarm Generation	• AIS • IDLE • Yellow
DS1 Error Injection	• DS1 bit errors
DS3 Error Injection	• F-bit invert • P-bit invert • CP-bit invert • C-bit FEBE • DS3 bit errors
PLCP Error Injection	• BPI error add • FEBE generation • C1 bit masking (DS3 only)
PLCP Overhead Stressing	• Normal and alternative values can be defined for overheads • Pulse or sequenec controls over normal and alternative overheads

ATM, PLCP, DS1 & DS3 Measurements

Measurements are sampled every 100 milliseconds and accumulated over the user-specified measurement period. Results from the most recent complete measurement period are retained.

Measurement Period	• Range 1 second to 3 days in resolutions of 1 second
Result Types	• Cumulative or latched (based on most recent measurement period)
Result Formats	• Count • Ratio • Seconds
ATM Cell Measurements	• Bad Headers • Selected Cell Count • Corrected headers • Cell loss count • Selected Cell bandwidth • Select Cell Not Received (SCNR) errored seconds
Cell Delay Measurements	• Cell delay • Inter-arrival time • Cell delay variation
Virtual Channel Errors	• AAL-1 SN/SNP errors • Cell loss • PRBS errors • PRBS sync loss alarm seconds
DS1 Measurements	• Code errors CRC-6 errors Loss of signal alarm seconds Out-of-frame alarm seconds AIS alarm seconds Yellow alarm seconds Frame count
DS3 Measurements	• Coding violations • Parity errors • C-bit parity errored seconds • FEBE errors • Loss of signal errored seconds • Out-of-frame errored seconds • AIS errored seconds • IDLE errored seconds • Yellow errored seconds • Frame count
PLCP Measurements	• BIP errors • FEBE errors • Trailer mismatches • OOF errored seconds • Yellow errored seconds • Frame count

Traffic Capture & Playback

ATM Capture

Provides capture of 1500 cells from the selected ATM cell stream. Capture is manual or event triggered. Manual triggering captures 1500 cells after the trigger. Event triggering captures 750 cells pre-trigger, and 750 cells post-trigger.

Manual	• Triggered on user request
ATM Cell Triggers	• Cell loss • Header error • PRBS error • SN/SNP byte error

PLCP Capture

Provides capture of 256 PLCP frames (overhead and ATM cell payload). Capture is manual or event triggered. Manual triggering captures 256 frames after the trigger. Event triggering captures 128 frames before and 128 frames after trigger.

Manual	• Triggered on user request
On Change	• Triggered when change detected in value of selected overhead byte. Selected bits of trigger byte can be disabled.

On Value	• Triggered when user defined value is detected in selected overhead byte. Any PLCP overhead byte can be selected as trigger byte.
On Event	• Triggered when defined PLCP event occurs (Yellow Alarm, FEBE, BIP, Error, Trailer Error)

Front Panel Connectors & Indicators

DS1 Input	• RJ48C or Bantam connector 100 ohm impedance 1.544 Mb/s 0 dB or -20 dB relative to High Xconnect and Low levels
DS1 Output	• RJ48C or Bantam connector • 75 ohm impedance • 1.544 Mb/s • Peak voltage may be set to High (9.5V), Xconnect (6.0V), and Low (3.8V) transmit levels • Internal (stratum 3), External, and Recovered clock modes
DS3 Input	• BNC connector • 75 ohm impedance • 44.736 Mb/s +/- 10 ppm • B3ZS code • 0 dB or -20 dB relative to High, Xconnect and Low levels
DS3 Output	• BNC connector • 75 ohm impedance • 44.736 Mb/s • B3ZS code • Peak voltage may be set to High (850 mV), Xconnect (710mV), and Low (300 mV) transmit levels • Internal (stratum 3), External, and Recovered clock modes
External Clock Input	• SNB connector • TTL input • Nominal 50 ohm impedance
Trigger Output	• SNB connector • TTL output • Nominal 50 ohm impedance
LED Indicators	• Failed • Error • Access • Gating • Signal • OOF • AIS • BIP • Yellow • SCNR • Reference Clock

Size, Weight, & Power Dissipation

Size	• 1 slot C-size VXI card
Weight	• 1.3 kg (2.9 lb) nominal
Power Dissipation	• 25 Watts (max)

Applicable Standards

ATM Cells	• ITU-T Recommendation I.361 1995 B- ISDN ATM layer specification • Bellcore TA-NWT-001113 1993 Asynchronous Transfer Mode and ATM Adaptation Layer (AAL) Protocols Generic Requirements
DS1/DS3 Frames	• ANSI T1.107-1995 Digital Hierarchy Formats Specifications • ITU-T G703 1991 Physical/Electrical Characteristics of Hierarchical Digital Interfaces • Bellcore TR-TSY-000499 Issue 5 Dec. 1993 Transport Systems: Generic Requirements (TSGR): Common Requirements
PLCP Frames	• IEEE 802.6 1994 Distributed Queue Dual Bus (DQDB) access method and physical layer specifications • Bellcore TR-TSV-000773 1993 Local Access Generic Requirements Objectives and Interfaces in Support of Switched Multi-megabit Data Service • ITU-T G.804 1993 ATM cell mapping into plesiochronous digital hierarchy • ATM Forum UNI Version 3.0 1993
Input & Output Signal	• ANSI T1.102-1993 Digital Hierarchy Electrical Interfaces
PRBS Patterns	• PRBS-9 as per ITU-T O.153 1992 • PRBS-23 as per ITU-T O.151 1992
EMC	• Meets FTZ 1046/1984 (CISPR11, EN 55011)

Agilent Technologies Broadband Series Test System

The Agilent Technologies BSTS is the industry-standard ATM/BISDN test system for R&D engineering, product development, field trials and QA testing. The latest leading edge, innovative solutions help you lead the fast-packet revolution and reshape tomorrow's networks. It offers a wide range of applications:

- ATM traffic management and signalling
- Packet over SONET/SDH (POS)
- switch/router interworking and performance
- third generation wireless tesing
- complete, automated conformance testing

The BSTS is modular to grow with your testing needs. Because we build all BSTS products without shortcuts according to full specifications, you'll catch problems other test equipment may not detect.

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